

Methods of measurement for waveguides —

Part 4: Attenuation of waveguide and waveguide assemblies

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National foreword

This British Standard is the UK implementation of EN 61580-4:1998, incorporating corrigendum July 2006. It is identical with IEC 61580-4:1997.

The start and finish of text introduced or altered by corrigendum is indicated in the text by tags. Text altered by IEC corrigendum July 2006 is indicated in the text by AC1 AC1.

The UK participation in its preparation was entrusted by Technical Committee EPL/46, Cables, wires and waveguides, r.f. connectors and accessories for communication and signalling, to Subcommittee EPL/46/2, Connectors and waveguides.

A list of organizations represented on this subcommittee can be obtained on request to its secretary.

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Methods of measurement for waveguides Part 4: Attenuation of waveguide and waveguide assemblies

(IEC 61580-4:1997)

Méthodes de mesure appliquées aux guides d'ondes
Partie 4: Atténuation des guides d'ondes et des ensembles de guides d'ondes
(CEI 61580-4:1997)

Meßverfahren für Hohlleiter
Teil 4: Dämpfung von Hohlleitern und Hohlleiterbauteilen
(IEC 61580-4:1997)

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CENELEC

European Committee for Electrotechnical Standardization
Comité Européen de Normalisation Electrotechnique
Europäisches Komitee für Elektrotechnische Normung

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Foreword

The text of document 46B/225/FDIS, future edition 1 of IEC 61580-4, prepared by SC 46B, Waveguides and their accessories, of IEC TC 46, Cables, wires, waveguides, R.F. connectors, and accessories for communication and signalling, was submitted to the IEC-CENELEC parallel vote and was approved by CENELEC as EN 61580-4 on 1998-04-01.

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- latest date by which the national standards conflicting with the EN have to be withdrawn (dow) 1999-01-01

Endorsement notice

The text of the International Standard IEC 61580-4:1997 was approved by CENELEC as a European Standard without any modification.

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